PATENT ABSTRACTS OF JAPAN

(11)Publication number:

2001-240625

(43)Date of publication of application: 04.09.2001

(51)Int.CI.

C08F220/28 C08F220/06 C08F220/18 C08F222/06 C08F232/08 C08K 5/00 C08L 33/14 G03F 7/039 H01L 21/027

(21)Application number: 2000-049549

(71)Applicant: TOSHIBA CORP

DAICEL CHEM IND LTD

2)Date of filing:

25.02.2000

(72)Inventor: GOKOCHI TORU

OKINO TAKASHI ASAKAWA KOUJI SHINODA NAOMI FUNAKI KATSUNORI TSUTSUMI KIYOHARU

HORAL AKIRA

(54) POLYMER COMPOUND FOR PHOTORESIST AND PHOTORESIST RESIN COMPOSITION

(57)Abstract:

PROBLEM TO BE SOLVED: To obtain a polymer compound for photoresist excellent in adhesiveness to a substrate and capable of forming fine patterns in good accuracy.

SOLUTION: This polymer compound for photoresist contains at least one species of monomer units selected from monomer units expressed by formula (Ia) and (Ib) (wherein R1, Ra, Rb, Rc, Rd, Re, and Rg are each the same or different and express H or methyl; X1, X2, and X3 are each -CH2- or -CO-Oand at least one of them expresses -CO-O-; m, p and q are each an integer of 0-2).

$$+ CH_2 - \stackrel{R^1}{\leftarrow} \rightarrow \\ \stackrel{C}{\leftarrow} 0$$

$$\stackrel{R^2}{\leftarrow} \stackrel{\chi^1}{\underset{R^b}{\vee}} \chi^3 - R^c$$

(Ia)

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application

BEST AVAILABLE COFY

converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]

Copyright (C); 1998,2003 Japan Patent Office